## CPC COOPERATIVE PATENT CLASSIFICATION

## H01C RESISTORS

## **NOTE**

In this subclass, the term "adjustable" means mechanically adjustable.

Variable resistors, the value of which is changed non-mechanically, e.g. by voltage or temperature, are classified in group <u>H01C 7/00</u>.

## **Guide heading:**

H01C 1/00	Details
H01C 1/01	. Mounting Supporting
H01C 1/012	the base extending along and imparting rigidity or reinforcement to the resistive element ( <u>H01C 1/016</u> takes precedence; the resistive element being formed in two or more coils or loops as a spiral, helical or toroidal winding <u>H01C 3/18</u> , <u>H01C 3/20</u> ; the resistive element being formed as one or more layers or coatings on a base <u>H01C 7/00</u> )
H01C 1/014	<ul> <li>the resistor being suspended between and being supported by two supporting sections (<u>H01C 1/016</u> takes precedence)</li> </ul>
H01C 1/016	with compensation for resistor expansion or contraction
H01C 1/02	. Housing Enclosing Embedding Filling the housing or enclosure
H01C 1/022	the housing or enclosure being openable or separable from the resistive element
H01C 1/024	the housing or enclosure being hermetically sealed ( <u>H01C 1/028</u> , <u>H01C 1/032</u> , <u>H01C 1/034</u> take precedence)
H01C 1/026	with gaseous or vacuum spacing between the resistive element and the housing or casing
H01C 1/028	the resistive element being embedded in insulation with outer enclosing sheath
H01C 1/03	with powdered insulation
H01C 1/032	plural layers surrounding the resistive element ( <u>H01C 1/028</u> takes precedence)
H01C 1/034	the housing or enclosure being formed as coating or mold without outer sheath (H01C 1/032 takes precedence)
H01C 1/036	on wound resistive element
H01C 1/04	. Arrangements of distinguishing marks, e.g. colour coding
H01C 1/06	. Electrostatic or electromagnetic shielding arrangements
H01C 1/08	. Cooling, heating or ventilating arrangements

H01C 1/082	using forced fluid flow
H01C 1/084	using self-cooling, e.g. fins, heat sinks
11040 4/40	
H01C 1/12	Arrangements of current collectors
H01C 1/125	of fluid contacts
H01C 1/14	Terminals or tapping points {or electrodes } specially adapted for resistors (in general H01R)  Arrangements of terminals or tapping points (or electrodes ) on recistors.
H04C 4/4406	Arrangements of terminals or tapping points (or electrodes ) on resistors
H01C 1/1406	{Terminals or electrodes formed on resistive elements having positive temperature coefficient }
H01C 1/1413	{Terminals or electrodes formed on resistive elements having negative temperature coefficient }
H01C 1/142	the terminals or tapping points being coated on the resistive element
H01C 1/144	the terminals or tapping points being welded or soldered
H01C 1/146	the resistive element surrounding the terminal
H01C 1/148	the terminals embracing or surrounding the resistive element ( <u>H01C 1/142</u> takes precedence)
H01C 1/16	. Resistor networks not otherwise provided for
H01C 3/00	Non-adjustable metal resistors made of wire or ribbon, e.g. coiled, woven or formed as grids
H01C 3/005	. {Metallic glasses therefor }
H01C 3/02	<ul> <li>arranged or constructed for reducing self-induction, capacitance or variation with frequency</li> </ul>
H01C 3/04	Iron-filament ballast resistors     Other resistors having variable temperature coefficient
H01C 3/06	<ul> <li>Flexible or folding resistors, whereby such a resistor can be looped or collapsed upon itself</li> </ul>
H01C 3/08	<ul> <li>Dimension or characteristic of resistive element changing gradually or in discrete steps from one terminal to another</li> </ul>
H01C 3/10	. the resistive element having zig-zag or sinusoidal configuration
H01C 3/12	Lying in one plane
H01C 3/14	<ul> <li>the resistive element being formed in two or more coils or loops continuously wound as a spiral, helical or toroidal winding (<u>H01C 3/02</u> to <u>H01C 3/12</u> take precedence)</li> </ul>
H01C 3/16	including two or more distinct wound elements or two or more winding patterns
H01C 3/18	wound on a flat or ribbon base ( <u>H01C 3/16</u> takes precedence)
H01C 3/20	wound on cylindrical or prismatic base (H01C 3/16 takes precedence)
H01C 7/00	Non-adjustable resistors formed as one or more layers or coatings Non-adjustable resistors made from powdered conducting material or powdered

semi-conducting material with or without insulating material (consisting of loose powdered or granular material H01C 8/00; { measuring deformation in a solid state using the change in resistance formed by printed-circuit technique G01B 7/20; insulating materials H01B 3/00; passive thin-film or thick-film semiconductor or solid state devices H01L 27/00; resistors without a potential-jump or surface barrier specially adapted for integrated circuits, details thereof, multistep manufacturing processes therefor H01L 28/20 }; resistors with a potential-jump barrier or surface barrier, e.g. field effect resistors H01L 29/00; semiconductor devices sensitive to electro-magnetic or corpuscular radiation, e.g. photoresistors, H01L 31/00; devices using superconductivity H01L 39/00; devices using galvanomagnetic or similar magnetic effects, e.g. magnetic-field-controlled resistors, H01L 43/00; solid state devices for rectifying, amplifying, oscillating or switching without a potential-jump barrier or surface barrier H01L 45/00; bulk negative resistance effect devices H01L 47/00; { ohmic resistance heating H05B 3/00; printed circuits H05K }) [m1112]

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H01C 7/001
                         {Mass resistors }
H01C 7/003
                         {Thick film resistors }
H01C 7/005
                            {Polymer thick films }
H01C 7/006
                         {Thin film resistors }
H01C 7/008
                         {Thermistors (H01C 7/02 to H01C 7/06 take precedence) }
H01C 7/02
                         having positive temperature coefficient { (ceramics C04B)}
H01C 7/021
                            {formed as one or more layers or coatings }
H01C 7/022
                            {mainly consisting of non-metallic substances (H01C 7/021 takes precedence) }
H01C 7/023
                               {containing oxides or oxidic compounds, e.g. ferrites }
H01C 7/025
                                  {Perowskites, e.g. titanates }
H01C 7/026
                                  {Vanadium oxides or oxidic compounds, e.g. VOx }
H01C 7/027
                            {consisting of conducting or semi-conducting material dispersed in a
                            non-conductive organic material }
H01C 7/028
                            {consisting of organic substances }
                         having negative temperature coefficient { (thermometers using resistive elements
H01C 7/04
                         G01K 7/16) }
H01C 7/041
                            {formed as one or more layers or coatings }
H01C 7/042
                            {mainly consisting of inorganic non-metallic substances (H01C 7/041 takes
                            precedence) }
                            NOTE
                                 In groups H01C 7/043 to H01C 7/049, in the absence of an indication to the
                                 contrary, classification is made in the last appropriate place
H01C 7/043
                               {Oxides or oxidic compounds }
                                  {Zinc or cadmium oxide }
H01C 7/044
H01C 7/045
                                  {Perowskites, e.g. titanates }
H01C 7/046
                                  {Iron oxides or ferrites }
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H01C 7/047	{Vanadium oxides or oxidic compounds, e.g. VOx }
H01C 7/048	{Carbon or carbides }
H01C 7/049	{mainly consisting of organic or organo-metal substances ( <u>H01C 7/041</u> takes precedence) }
H01C 7/06	. including means to minimise changes in resistance with changes in temperature
H01C 7/10	. voltage responsive, i.e. varistors
H01C 7/1006	{Thick film varistors }
H01C 7/1013	{Thin film varistors }
H01C 7/102	Varistor boundary, e.g. surface layers ( <u>H01C 7/12</u> takes precedence)
H01C 7/105	Varistor cores ( <u>H01C 7/12</u> takes precedence)
H01C 7/108	Metal oxide
H01C 7/112	ZnO type
H01C 7/115	Titanium dioxide- or titanate type
H01C 7/118	Carbide, e.g. SiC type
H01C 7/12	<ul> <li>Overvoltage protection resistors { (series resistors structurally associated with spark gaps <u>H01T 1/16</u>) }</li> </ul>
H01C 7/123	{Arrangements for improving potential distribution }
H01C 7/126	{Means for protecting against excessive pressure or for disconnecting in case of failure }
H01C 7/13	. current responsive
	<u>NOTE</u>
	Groups H01C 7/02 to H01C 7/13 take precedence over groups H01C 7/18 to
	H01C 7/22.
H01C 7/18	
H01C 7/18 H01C 7/20	H01C 7/22.
	H01C 7/22.  comprising a plurality of layers stacked between terminals
H01C 7/20	<ul> <li>H01C 7/22.</li> <li>comprising a plurality of layers stacked between terminals</li> <li>the resistive layer or coating being tapered</li> </ul>
H01C 7/20 H01C 7/22	<ul> <li>H01C 7/22.</li> <li>comprising a plurality of layers stacked between terminals</li> <li>the resistive layer or coating being tapered</li> <li>Elongated resistive element being bent or curved, e.g. sinusoidal, helical</li> <li>Non-adjustable resistors consisting of loose powdered or granular conducting, or</li> </ul>
H01C 7/20 H01C 7/22 H01C 8/00	<ul> <li>H01C 7/22.</li> <li>comprising a plurality of layers stacked between terminals</li> <li>the resistive layer or coating being tapered</li> <li>Elongated resistive element being bent or curved, e.g. sinusoidal, helical</li> <li>Non-adjustable resistors consisting of loose powdered or granular conducting, or powdered or granular semi-conducting material</li> </ul>
H01C 7/20 H01C 7/22 H01C 8/00 H01C 8/02	<ul> <li>Ho1C 7/22.</li> <li>comprising a plurality of layers stacked between terminals</li> <li>the resistive layer or coating being tapered</li> <li>Elongated resistive element being bent or curved, e.g. sinusoidal, helical</li> <li>Non-adjustable resistors consisting of loose powdered or granular conducting, or powdered or granular semi-conducting material</li> <li>Coherers or like imperfect resistors for detecting electromagnetic waves</li> <li>Overvoltage protection resistors</li> </ul>

H01C 10/02	. Liquid resistors
H01C 10/025	{Electrochemical variable resistors (trimming resistors by electrolytic treatment H01C 17/2412, H01C 17/262) }
H01C 10/04	<ul> <li>with specified mathematical relationship between movement of resistor actuating means and value of resistance, other than direct proportional relationship</li> </ul>
H01C 10/06	. adjustable by short-circuiting different amounts of the resistive element
H01C 10/08	<ul> <li>with intervening conducting structure between the resistive element and the short-circuiting means, e.g. taps</li> </ul>
H01C 10/10	adjustable by mechanical pressure of force
H01C 10/103	{by using means responding to magnetic or electric fields, e.g. by addition of magnetisable or piezoelectric particles to the resistive material, or by an electromagnetic actuator }
H01C 10/106	{on resistive material dispersed in an elastic material ( <u>H01C 10/103</u> and <u>H01C 10/12</u> take precedence; for electric switches <u>H01H 1/02B</u> ) }
H01C 10/12	<ul> <li>by changing surface pressure between resistive masses or resistive and conductive masses, e.g. pile type</li> </ul>
H01C 10/14	adjustable by auxiliary driving means
H01C 10/16	. including plural resistive elements
H01C 10/18	including coarse and fine resistive elements
H01C 10/20	Contact structure or movable resistive elements being ganged
H01C 10/22	<ul> <li>resistive element dimensions changing gradually in one direction, e.g. tapered resistive element (<u>H01C 10/04</u> takes precedence)</li> </ul>
H01C 10/23	. resistive element dimensions changing in a series of discrete, progressive steps
H01C 10/24	. the contact moving along turns of a helical resistive element, or vica versa
H01C 10/26	. resistive element moving ( <u>H01C 10/16</u> , <u>H01C 10/24</u> take precedence)
	<u>NOTE</u>
	Groups $\underline{\text{H01C }10/02}$ to $\underline{\text{H01C }10/26}$ take precedence over groups $\underline{\text{H01C }10/50}$ .
H01C 10/28	. the contact rocking or rolling along resistive element or taps
H01C 10/30	the contact sliding along resistive element
H01C 10/301	{consisting of a wire wound resistor }
H01C 10/303	{the resistor being coated, e.g. lubricated, conductive plastic coated, i.e. hybrid potentiometer }
H01C 10/305	{consisting of a thick film }
H01C 10/306	{Polymer thick film, i.e. PTF }
H01C 10/308	{consisting of a thin film }
2 1 2 1 3, 3 3	(

H01C 10/32	the contact moving in an arcuate path
H01C 10/34	
HUTC 10/34	the contact or the associated conducting structure riding on collector formed as a ring or portion thereof
H01C 10/345	{the collector and resistive track being situated in 2 parallel planes }
H01C 10/36	structurally combined with switching arrangements
H01C 10/363	{by axial movement of the spindle, e.g. pull-push switch ( <u>H01C 10/366</u> takes precedence) }
H01C 10/366	{using an electromagnetic actuator }
H01C 10/38	the contact moving along a straight path
H01C 10/40	screw operated
H01C 10/42	the contact bridging and sliding along resistive element and parallel conducting bar or collector
H01C 10/44	the contact bridging and sliding along resistive element and parallel conducting bar or collector ( <u>H01C 10/42</u> takes precedence)
H01C 10/46	<ul> <li>Arrangements of fixed resistors with intervening connectors, e.g. taps (<u>H01C 10/28</u>, <u>H01C 10/30</u> take precedence)</li> </ul>
H01C 10/48	including contact movable in an arcuate path
H01C 10/50	. structurally combined with switching arrangements ( <u>H01C 10/36</u> takes precedence)
H01C 11/00	Non-adjustable liquid resistors
H01C 13/00	Resistors not provided for elsewhere
H01C 13/00 H01C 13/02	Resistors not provided for elsewhere  . Structural combinations of resistors (impedance networks per se H03H)
H01C 13/02	Structural combinations of resistors (impedance networks per se <u>H03H</u> ) <b>Apparatus or processes specially adapted for manufacturing resistors</b> (providing fillings for housings or enclosures <u>H01C 1/02</u> ; reducing insulation surrounding a resistor
H01C 13/02 H01C 17/00	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in</li> </ul>
H01C 13/02 H01C 17/00 H01C 17/003	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}</li> </ul>
H01C 13/02 H01C 17/00 H01C 17/003 H01C 17/006	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}</li> <li>{adapted for manufacturing resistor chips}</li> </ul>
H01C 13/02 H01C 17/00  H01C 17/003 H01C 17/006 H01C 17/02	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}</li> <li>{adapted for manufacturing resistor chips}</li> <li>adapted for manufacturing resistors with envelope or housing</li> </ul>
H01C 13/02 H01C 17/00  H01C 17/003 H01C 17/006 H01C 17/02 H01C 17/04	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}</li> <li>{adapted for manufacturing resistor chips}</li> <li>adapted for winding the resistive element</li> </ul>
H01C 13/02 H01C 17/00  H01C 17/003 H01C 17/006 H01C 17/02 H01C 17/04 H01C 17/06	Structural combinations of resistors (impedance networks per se H03H)  Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)      {using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}      {adapted for manufacturing resistor chips}      adapted for manufacturing resistors with envelope or housing      adapted for winding the resistive element      adapted for coating resistive material on a base
H01C 13/02 H01C 17/00  H01C 17/003  H01C 17/006 H01C 17/04 H01C 17/06 H01C 17/065	Structural combinations of resistors (impedance networks per se H03H)  Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)  - {using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}  - {adapted for manufacturing resistor chips}  - adapted for winding the resistive element  - adapted for coating resistive material on a base  - by thick film techniques, e.g. serigraphy
H01C 13/02 H01C 17/00  H01C 17/003  H01C 17/006 H01C 17/04 H01C 17/06 H01C 17/065 H01C 17/06506	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}</li> <li>{adapted for manufacturing resistor chips}</li> <li>adapted for winding the resistive element</li> <li>adapted for coating resistive material on a base</li> <li>by thick film techniques, e.g. serigraphy</li> <li>{Precursor compositions therefor, e.g. pastes, inks, glass frits}</li> </ul>
H01C 13/02 H01C 17/00  H01C 17/003  H01C 17/006 H01C 17/02 H01C 17/04 H01C 17/065 H01C 17/06506 H01C 17/06513	<ul> <li>Structural combinations of resistors (impedance networks per se H03H)</li> <li>Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)</li> <li>{using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}</li> <li>{adapted for manufacturing resistor chips}</li> <li>adapted for winding the resistive element</li> <li>adapted for coating resistive material on a base</li> <li>by thick film techniques, e.g. serigraphy</li> <li>{Precursor compositions therefor, e.g. pastes, inks, glass frits}</li> <li>{characterised by the resistive component}</li> </ul>
H01C 13/02 H01C 17/00  H01C 17/003  H01C 17/006 H01C 17/04 H01C 17/06 H01C 17/065 H01C 17/06506 H01C 17/06513 H01C 17/0652	. Structural combinations of resistors (impedance networks per se H03H)  Apparatus or processes specially adapted for manufacturing resistors (providing fillings for housings or enclosures H01C 1/02; reducing insulation surrounding a resistor to powder H01C 1/03; manufacture of thermally variable resistors H01C 7/02, H01C 7/04)  · {using lithography, e.g. photolithography (lithographic compositions and processing in general G03F)}  · {adapted for manufacturing resistor chips}  · adapted for manufacturing resistors with envelope or housing  · adapted for coating resistive element  · adapted for coating resistive material on a base  · by thick film techniques, e.g. serigraphy  · {Precursor compositions therefor, e.g. pastes, inks, glass frits}  · {characterised by the resistive component}  · {containing carbon or carbides}

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H01C 17/0654
                                         {Oxides of the platinum group }
                      . . . . . .
H01C 17/06546
                                         {Oxides of zinc or cadmium }
                      . . . . . .
H01C 17/06553
                                      {composed of a combination of metals and oxides }
H01C 17/0656
                                      {composed of silicides (H01C 17/0652 takes precedence) }
H01C 17/06566
                                     {composed of borides (H01C 17/0652 takes precedence) }
H01C 17/06573
                                  {characterised by the permanent binder }
H01C 17/0658
                                      {composed of inorganic material }
H01C 17/06586
                                      {composed of organic material }
H01C 17/06593
                                  {characterised by the temporary binder }
H01C 17/07
                            by resistor foil bonding, e.g. cladding
                      . .
                            by thin film techniques { (H01C 17/20 takes precedence) }
H01C 17/075
                      . .
H01C 17/08
                               by vapour deposition
H01C 17/10
                               by flame spraying
H01C 17/12
                               by sputtering
H01C 17/14
                               by chemical deposition
H01C 17/16
                                  using electric current
H01C 17/18
                                  without using electric current
H01C 17/20
                            by pyrolytic processes
H01C 17/22
                         adapted for trimming
H01C 17/23
                            by opening or closing resistor geometric tracks of predetermined resistive values,
                            {e.g. snapistors }
H01C 17/232
                            Adjusting the temperature coefficient
                            Adjusting value of resistance by adjusting temperature coefficient of resistance
H01C 17/235
                            Initial adjustment of potentiometer parts for calibration
H01C 17/24
                            by removing or adding resistive material (H01C 17/23, H01C 17/232, H01C 17/235
                            take precedence)
H01C 17/2404
                               {by charged particle impact e.g. by electron or ion beam milling, sputtering,
                      . . .
                               plasma etching }
H01C 17/2408
                               {by pulsed voltage erosion, e.g. spark erosion }
H01C 17/2412
                               (by electrolytic treatment e.g. electroplating (for anodic oxydation H01C 17/262)
H01C 17/2416
                               {by chemical etching }
H01C 17/242
                               by laser { (trimming by laser in general B23K 26/0003) }
H01C 17/245
                               by mechanical means, e.g. sand blasting, cutting, ultrasonic treatment
H01C 17/26
                            by converting resistive material
H01C 17/262
                               {by electrolytic treatment, e.g. anodic oxydation }
H01C 17/265
                               {by chemical or thermal treatment, e.g. oxydation, reduction, annealing (etching
                               H01C 17/2416) }
H01C 17/267
                                  {by passage of voltage pulses or electric current }
H01C 17/28
                         adapted for applying terminals
H01C 17/281
                            {by thick film techniques }
H01C 17/283
                               {Precursor compositions therefor, e.g. pastes, inks, glass frits }
                      . . .
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H01C 17/285 .... {applied to zinc or cadmium oxide resistors }
H01C 17/286 .... {applied to TiO2 or titanate resistors }
H01C 17/288 ... {by thin film techniques }
H01C 17/30 . adapted for baking
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